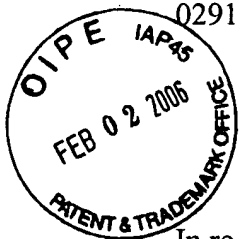


IFW

02910.000114

PATENT APPLICATION



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

MUNEKI ANDO

Application No.: 10/762,252

Filed: January 23, 2004

For: IMAGE SIGNAL PROCESSING  
APPARATUS AND METHOD AND  
IMAGE DISPLAY APPARATUS  
AND METHOD

)  
: Examiner: Unassigned  
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: Group Art Unit: 2621  
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) February 2, 2006  
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Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

FIRST SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed Form PTO-1449. Copies of the listed Japanese documents are also enclosed.

Japanese Patent Document No. 63-306496 discloses a simple matrix liquid crystal display that selects a plurality of scanning electrodes simultaneously in order to improve the contrast ratio. It also indicates that, in the scanning method, selecting simultaneously a plurality of scanning electrodes causes deterioration of a high frequency transfer characteristic of spatial frequency, and discloses an edge enhancement circuit that compensates for deterioration

in high-frequency. It also discloses that the method of improving luminance and contrast disclosed therein is applicable as the method for improving luminance and contrast display elements such as plasma display elements, EL and a CRT.

Japanese Patent Document No. 8-50462 discloses driving a plurality of scanning lines simultaneously in a flat panel display with hot cathodes. It also discloses that by using a high emphasis filter that emphasize the luminance of the edge part where the value of the tone signal changes rapidly, deterioration of resolution in a vertical direction caused by driving a plurality of scanning lines simultaneously is alleviated.

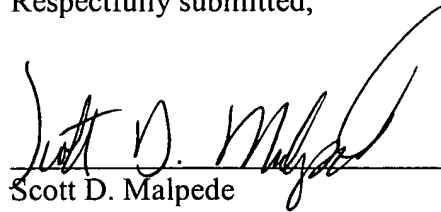
Applicant certifies under 37 C.F.R. §1.97(e)(1) that each item of information contained in the subject information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement. Specifically, these documents were first cited in a Japanese Office Action dated November 15, 2005, in a corresponding Japanese patent application. A copy of the Office Action that issued on that related application is enclosed.

#### CONCLUSION

It is respectfully requested that the above information be considered by the Examiner and that an initialed copy of the enclosed Form PTO-1449 be returned indicating that such information has been considered.

Applicant's undersigned attorney may be reached in our Washington, D.C.  
office by telephone at (202) 530-1010. All correspondence should continue to be directed to our  
address given below.

Respectfully submitted,



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Scott D. Malpede  
Attorney for Applicant  
Registration No. 32,533

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New York, New York 10112-3801  
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SDM\mm

DC\_MAIN 229204v1

FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)  
(Use several sheets if necessary)

Submitted to the PTO: February 2, 2006

ATTY DOCKET NO.  
**02910.000114****FEB 02 2006**APPLICATION NO.  
**10/762,252**APPLICANT  
**MUNEKI ANDO**FILING DATE  
**January 23, 2004**GROUP  
**2621**

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
		<b>63-306496</b>	<b>12/1988</b>	<b>Japan</b>			<b>No</b>
		<b>8-50462</b>	<b>02/1996</b>	<b>Japan</b>			<b>Abstract</b>

## OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)


EXAMINER

DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.